## **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

STRUCTURE AND METHOD FOR SILICIDED METAL GATE TRANSISTORS

Application Number:

10/605, 130

Confirmation Number:

First Named Applicant:

**Bruce Doris** 

Attorney Docket Number:

FIS920030283US1

Art Unit:

Examiner:

Search string:

( 6033963 or 6492694 or 6528362 or 6534352 or 6544827 or 6589866 or

20030122202).pn

## **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
BU	1	6033963	2000-03-07	Huang, et al.	1		
1	2	6492694	2002-12-10	Nobel, et al.			
	3	6528362	2003-03-04	Besser, et al.			
	4	6534352	2003-03-18	Kim			
	5	6544827	2003-04-08	Abiko			
B	6	6589866	2003-07-08	Besser, et al.		•	

## **US Published Applications**

Note: Applicant is not required to submit a paper copy of cited US Published Applications

init Cite.No	Pub. No.	Date	Applicant	Kind	Class	Subclass
D1 1	20030122202	2003-07-03	Kwon			

Signature

Examiner Name Date

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FORM PTO-1449 (Modified)  SEP 2 9 2003  LIST OF PATENTS AND PUBLICATIONS FOR APECANT'S INFORMATION DISCLOSURE STOPMENT				ATTY. DOCKET NO. FIS920030283US1	.			30	
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							YES	NO	
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	AJ	F. F. Zhao et al., "Silicon Materials – Processing, Characterization and Reliability Symposium,"  Mater. Res. Soc. Proc., vol. 716, 2002, pp. 41-46.							
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